

संत लौंगोवाल अभियांत्रिकी एवं प्रौद्योगिकी संस्थान

(मानव संसाधन विकास मंत्रालय, भारत सरकार के अधीन सम विश्वविद्यालय)

लौंगोवाल, जिला-संगरूर, पंजाब - 148106

Sant Longowal Institute of Engineering & Technology

(Deemed to be-University under Ministry of Human Resource Development, Government of India)

Longowal, Distt. Sangrur, Punjab-148106

संदर्भ सं/ Ref.No. SLIET/CF/184

दिनांक / Date: 07-01-2021

CIRCULAR

Field Emission Scanning Electron Microscope (FESEM) [Model: JEOL JSM 7610 F PLUS] along with Energy Dispersive Spectrometer (EDS)[Make: EDAX and APEX software] are in operation in the institute and are open for the testing/analysis of the materials on charge basis. The following charges are fixed for testing/analysis of various samples.

| For SLIET | | Other Educational Institutions | R &D Labs and Industry |
|-----------------------------------|---|---|---|
| FE-SEM (Surface OR Cross-Section) | 500/- per sample with Au coating. 400/- per sample without coating. | 800/- per sample with Au coating. 700/- per sample without coating. | R&D Labs: 1500/- with Au coating. 1250/- without Au coating. Industry: 2500/- with coating and 2000/- without coating. |
| EDS (Area/Spot/Line Scan) | 150/-per sample | 250/- per sample. | R&D Labs: 500/- per sample Industry: 1000/- per sample |
| EDS-Mapping | 250/- per sample. | 500/- per sample | R&D Labs: 750/- per sample Industry: 1000/- per sample |

Maximum eight photographs per sample on FESEM are allowed, further 9-16 images may be counted as two samples, and so on.

Faculty members of the institute, who have already opted for paying Rs. 5000.00 per annum from PDA for using the facilities available as Central Facility in the institute, shall be exempted to pay these charges.

Chairman, Central Facility Lab

CC to

Director

All Deans

All HODs: with a request to circulate among faculty members

Registrar

DR(A&A): with a request to make necessary arrangement for collecting the charges for samples

testing/analysis

ACSS: for uploading on institute website with a link as FESEM and EDS system Testing/Analysis